CE EMC COMPLIANCE TEST REPORT

For

USB2.0 IDE/SATA ADAPTER

Trade Name	:	UNITEK	
Model Number	:	Y-103	
Serial Number	:	N/A	
Report Number	:	SZ060424B02-ET	
Date	:	August 01, 2006	
Regulations	:	See below	
Standards			Results (Pass/Fail)
EN 55022: 1998+A1: 2000+A	2:2	003	PASS
EN 61000-3-2: 2000			PASS
EN 61000-3-3: 1995+A1:2001			PASS
EN 55024: 1998+A1: 2001+A2: 2003			
- IEC 61000-4-2: 2001			PASS
- IEC 61000-4-3: 2002			PASS
- IEC 61000-4-4: 2001			PASS
- IEC 61000-4-5: 2001			PASS
- IEC 61000-4-6: 2001			PASS
- IEC 61000-4-11: 2001			PASS

Prepared for : TECH-TOP TECHNOLOGY LIMITED RM 1609/1611, METRO CENTRE II 21 LAM HING STREET, KOWLOON BAY KOWLOON, HONGKONG

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TEST RESULT CERTIFICATION

Equipment Under Test:	USB2.0 IDE/SATA ADAPTER
Trade Name:	UNITEK
Model Number:	Y-103
Serial Number:	N/A
Applicant:	TECH-TOP TECHNOLOGY LIMITED RM 1609/1611, METRO CENTRE II 21 LAM HING STREET, KOWLOON BAY KOWLOON, HONGKONG
Manufacturer:	OCEAN COMPUTER TECHNOLOGY(SHENZHEN) CO., LTD 3/F, BLOCK 10, CHANG XIN IND. CITY, CHANG ZHEN VILLAGE, GONG MING TOWN, BAOAN, SHENZHEN
Type of Test:	EMC Directive 89/336/EEC for CE Marking
Technical Standards:	EN 55022: 1998+A1: 2000+A2: 2003 EN 61000-3-2: 2000 EN 61000-3-3: 1995+A1: 2001 EN 55024: 1998+A1: 2001+A2: 2003 (IEC 61000-4-2: 2001; IEC 61000-4-3: 2002; IEC 61000-4-4: 2001; IEC 61000-4-5: 2001; IEC 61000-4-6: 2001; IEC 61000-4-11: 2001)
Report Number:	SZ060424B02-ET
Date of test:	April 24~August 01, 2006
Deviation:	None
Condition of Test Sample:	Normal

The above equipment was tested by Compliance Certification Services (Shenzhen) Inc. for compliance with the requirements set forth in EMC Directive 89/336/EEC amended by 93/68/EEC and the Technical Standards mentioned above. This said equipment in the configuration described in this report shows the maximum emission levels emanating from equipment and the level of the immunity endurance of the equipment are within the compliance requirements.

The test results of this report relate only to the tested sample identified in this report.

Approved By:

Harris Lai / General Manager COMPLIANCE CERTIFICATION SERVICES (SHENZHEN) INC.

Tested By:	Jason He
	- 1 /
Reviewed By:	Un
	Villian XII / Assistant manager

Villian Xu / Assistant manager COMPLIANCE CERTIFICATION SERVICES (SHENZHEN) INC.

GENERAL INFORMATION

	RM 1609/1611, METRO CENTRE II 21 LAM HING STREET, KOWLOON BAY KOWLOON, HONGKONG
Manufacturer:	OCEAN COMPUTER TECHNOLOGY(SHENZHEN) CO., LTD 3/F, BLOCK 10, CHANG XIN IND. CITY, CHANG ZHEN VILLAGE, GONG MING TOWN, BAOAN, SHENZHEN
Report Number:	SZ060424B02-ET
Date of Test:	April 24~August 01, 2006
Equipment Under Test:	USB2.0 IDE/SATA ADAPTER
Model Number:	Y-103
Serial Number:	N/A
Type of Test:	EMC Directive 89/336/EEC for CE Marking
Technical Standards:	EN 55022: 1998+A1: 2000+A2: 2003 EN 61000-3-2: 2000 EN 61000-3-3: 1995+A1: 2001 EN 55024: 1998+A1: 2001+A2: 2003 (IEC 61000-4-2: 2001; IEC 61000-4-3: 2002; IEC 61000-4-4: 2001; IEC 61000-4-5: 2001; IEC 61000-4-6: 2001; IEC 61000-4-11: 2001)
Technical Standards: Frequency Range	EN 55022: 1998+A1: 2000+A2: 2003 EN 61000-3-2: 2000 EN 61000-3-3: 1995+A1: 2001 EN 55024: 1998+A1: 2001+A2: 2003 (IEC 61000-4-2: 2001; IEC 61000-4-3: 2002; IEC 61000-4-4: 2001; IEC 61000-4-5: 2001; IEC 61000-4-6: 2001; IEC 61000-4-11: 2001) 150kHz to 30MHz for Line Conducted Test
Technical Standards: Frequency Range (EN 55022):	EN 55022: 1998+A1: 2000+A2: 2003 EN 61000-3-2: 2000 EN 61000-3-3: 1995+A1: 2001 EN 55024: 1998+A1: 2001+A2: 2003 (IEC 61000-4-2: 2001; IEC 61000-4-3: 2002; IEC 61000-4-4: 2001; IEC 61000-4-5: 2001; IEC 61000-4-6: 2001; IEC 61000-4-11: 2001) 150kHz to 30MHz for Line Conducted Test 30MHz to 1000MHz for Radiated Emission Test

SYSTEM DESCRIPTION

EUT Test Program:

- 1. Set up the EUT with the related support equipments.
- 2. Run the Copy.bat program of transferring data from PC to hard disk in windows XP.
- 3. Make sure EUT work normally during the test.

PRODUCT INFORMATION

Housing Type:	Plastic
EUT Power Rating:	DC5V supplied by the adapter and PC
Power during Test:	DC5V supplied by the adapter and PC
Adapter Manufacturer/Model No:	FLYPOWER/ SPP34-12.0/5.0-2000 Cable in: Un-shielded, 1.90m Cable out: Un-shielded, 0.75m
USB Cable:	Shielded, 0.65m (with six cores)
SATA Data Link Cable:	Shielded, 0.10m
DC Diffluent Cable:	Shielded, 0.10m

I/O Port of EUT:

	I/O Port Type	Q'TY	Tested with
1)	AC Input Port (Adapter)	1	1
2)	DC Output Port (Adapter)	1	1
3)	DC Input Port (EUT)	1	1
4)	UNITEK DC Input Port	1	1
5)	SATA Input Port	1	1
6)	IDE Input Port	1	1
7)	ATC Input Port	1	1
8)	USB Port	1	1

Difference between model numbers as below:

	Model Number	Trade Name
1.	N/A	N/A

SUPPORT EQUIPMENT

No.	Equipment	Model #	Serial #	Trade Name	Data Cable	Power Cord
1.	РС	DX6100MT	CNG4470CNW	HP	N/A	Unshielded 1.8m
2.	LCD MONITOR	VP2016	A21050402549	VIEWSONIC	Shielded 1.5 m	Unshielded 1.8m
3.	PRINTER	P310B	DLRE217030	EPSON	Shielded 1.5 m	Unshielded 1.8m
4.	MODEM	MODEN-1414	9013593	ACEEX	Shielded 1.5m	Unshielded 1.8m
5.	PS/2 KEYBOARD	LG1M-K818	LGKL0308856	LG	Shielded 1.8 m	N/A
6.	PS/2 MOUSE	M-BE58	LZA24503529	LOGITECH	Shielded 1.8 m	N/A
7.	IDE DISK	6L080PO	BAJ41G20	MAXTOR	N/A	N/A
8.	SATA DISK	6V080EO	VA131610	MAXTOR	N/A	N/A

****Note:** All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test.

Grounding: Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.

TEST FACILITY

Location:	No. 5, Jinao industrial park, No.35 Jukeng Road, Dashuikeng Village, Guanlan Town, Baoan District Shenzhen, China.
Description:	There is one 3/10m open area test sites and one line conducted labs for final test. The Open Area Test Sites and the Line Conducted labs are constructed and calibrated to meet the FCC requirements in documents ANSI C63.4 and CISPR 22/EN 55022 requirements.
Site Filing:	A site description is on file with the Federal Communications Commission, 7435 Oakland Mills Road, Columbia, MD 21046.
Site Accreditation:	Accredited by Nemko (Aut. No.: ELA106), VCCI(Registration No.: R-1996,C-2150), FCC (Registration No.: 101879) and NVLAP(Lab code:200577-0) for EMC.
Instrument Tolerance:	All measuring equipment is in accord with ANSI C63.4 and CISPR 22 requirements that meet industry regulatory agency and accreditation agency requirement.

Ground Plane: Two conductive reference ground planes were used during the Line Conducted Emission, one in vertical and the other in horizontal. The dimensions of these ground planes are as below. The vertical ground plane was placed distancing 40 cm to the rear of the wooden test table on where the EUT and the support equipment were placed during test. The horizontal ground plane projected 50 cm beyond the footprint of the EUT system and distanced 80 cm to the wooden test table. For Radiated Emission Test, one horizontal conductive ground plane extended at least 1m beyond the periphery of the EUT and the largest measuring antenna, and covered the entire area between the EUT and the antenna. It has no holes or gaps having longitudinal dimensions larger than one-tenth of a wavelength at the highest frequency of measurement up to 1GHz.

TEST EQUIPMENT LIST

Instrumentation: The following list contains equipment used at Compliance Certification Services (Shenzhen) Inc. for testing. The equipment conforms to the CISPR 16-1 / ANSI C63.2 Specifications for Electromagnetic Interference and Field Strength Instrumentation from 10kHz to 1.0GHz or above. **Equipment used during the tests:**

Open Area Test Site: G

Open Area Test Site G						
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE	
ESCI EMI TEST RECEIV.ESCI	ROHDE&SCH WARZ	1166.5950 03	100145	02/09/2006	02/08/2007	
Amplifier	H.P.	8447D	2944A07999	02/09/2006	02/08/2007	
Bi-log Antenna	EMCO	3142B	9910-1436	06/10/2006	06/09/2007	
Cable	TIME MICROWAVE	LMR-400	N-TYPE04	06/10/2006	06/09/2007	
System-Controller	СТ	SC100	N/A	N/A	N/A	
Turn Table	EMCO	2081-1.21	N/A	N/A	N/A	
Antenna Tower	СТ	N/A	N/A	N/A	N/A	
DECOUPLING NETWORK	FISCHER CUSTOM	F-201-DCN-5 -6MM	12	06/10/2006	06/09/2007	

Note: The measure uncertainty is less than +/-2.5078dB, which is evaluated as per the UKAS LAB34 and CISPR/A/291/CDV.

Conducted Emission Test Site: G

Conducted Emission Test Site G								
EQUIPMENT	EQUIPMENT MFR MODEL SERIAL I							
TYPE		NUMBER	NUMBER	CAL.	DUE			
ESCI EMI TEST	ROHDE&SCH	1166 5050 02	100088	02/00/2006	02/08/2007			
RECEIV.ESCI	WARZ	1100.3930 03	100088	02/09/2000	02/08/2007			
LISN	EMCO	3825/2	1371	02/09/2006	02/08/2007			
LISN	EMCO	3825/2	8901-1459	02/09/2006	02/08/2007			

Note: The measure uncertainty is less than +/-2.2318dB, which is evaluated as per the UKAS LAB34 and CISPR/A/291/CDV.

The calibrations of the measuring instruments, including any accessories that may effect such calibration, are checked frequently to assure their accuracy. Adjustments are made and correction factors applied in accordance with instructions contained in the manual for the measuring instrument.



TEST EQUIPMENT LIST

Power Harmonic & Voltage Fluctuation/Flicker Measurement (61000-3-2&-3-3)								
EQUIPMENT	MFR	MODEL	SERIAL	LAST	CAL DUE.			
TYPE		NUMBER	NUMBER	CAL.				
Harmonic & Flicker	SCHAEENED	NSG	54780	02/00/2006	02/08/2007			
Tester	SCHAITMER	1007-5-400	54769	02/09/2000	02/08/2007			
Power Source	SCHAFFNER	NSG1007	54789	02/09/2006	02/08/2007			

ESD test (61000-4-2)						
EQUIPMENT	MFR	MODEL	SERIAL	LAST	CAL DUE.	
TYPE		NUMBER	NUMBER	CAL.		
ESD 30 System	EM Test	ESD 30C	1202-17	10/18/2006	10/17/2007	

Radiated Electromagnetic Field immunity Measurement (61000-4-3)								
EQUIPMENT	MFR	MODEL	SERIAL	LAST	CAL DUE.			
TYPE		NUMBER	NUMBER	CAL.				
Signal Generator	Maconi	2022D	119246/003	06/10/2006	06/09/2007			
Power Amplifier	M2S	A00181-1000	9801-112	06/10/2006	06/09/2007			
Power Amplifier	M2S	AC8113/ 800-250A	9801-179	06/10/2006	06/09/2007			
Power Antenna	SCHAFFNER	CBL6140A	1204	06/10/2006	06/09/2007			

Fast Transients/Burst test (61000-4-4)/Surge(61000-4-5)/Voltage Dips							
	&Inter	ruptions(6100	0-4-11)				
EQUIPMENT	MFR	MODEL	SERIAL	LAST	CAL DUE.		
TYPE		NUMBER	NUMBER	CAL.			
Fast Transients/Burst Generator	SCHAFFNER	BEST EMC V2.7	200126-012S C	02/09/2006	02/08/2007		

CS test (61000-4-6)							
EQUIPMENT MFR MODEL SERIAL				LAST	CAL DUE.		
TYPE		NUMBER	NUMBER	CAL.			
Signal Generator	Maconi	2022D	119246/003	06/10/2006	06/09/2007		
Power Amplifier	M2S	A00181-1000	9801-112	06/10/2006	06/09/2007		
CDN	MEB	M3-8016	003683	06/10/2006	06/09/2007		

SECTION 1 EN 55022(LINE CONDUCTED AND RADIATED EMISSION) MEASUREMENT PROCEDURE (PRELIMINARY LINE CONDUCTED EMISSION TEST)

- 1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN55022.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN55022.
- 4) The EUT received DC5V from the adapter and PC, then the adapter and PC received AC230V/50Hz power through a Line Impedance Stabilization Network (LISN) which supplied power source and was grounded to the ground plane.
- 5) All support equipments received power from a second LISN supplying power of AC 230V/50Hz, if any.
- 6) The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum Analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- 7) Analyzer / Receiver scanned from 150kHz to 30MHz for emissions in each of the test modes.
- 8) During the above scans, the emissions were maximized by cable manipulation.
- 9) The following test mode(s) were scanned during the preliminary test:

Preliminary Conducted Emission Test						
Frequency Range Investigated 150KHz TO 30 MHz						
Mode of operation	Date	Data Report No.	Worst Mode			
SATA DISK	2006-07-28	Y-103_0(L, N)	\boxtimes			
IDE DISK	2006-07-28	Y-103_1(L, N)				

Then, the EUT configuration and cable configuration of the above highest emission level were recorded for reference of final testing.

MEASUREMENT PROCEDURE (FINAL LINE CONDUCTED EMISSION TEST)

- 1) EUT and support equipment was set up on the test bench as per step 9 of the preliminary test.
- 2) A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less -2dB to the A.V. limit in Peak mode, then the emission signal was re-checked using Q.P and Average detector.
- 3) The test data of the worst case condition(s) was reported on the Summary Data page.

Data Sample:

Freq.	Peak	Q.P.	Average	Q.P.	Average	Q.P.	Average	Note
MHz	Raw	Raw	Raw	Limit	Limit	Margin	Margin	
	dBuV	dBuV	dBuV	dBuV	dBuV	dB	dB	
XX.XXX	43.90			56.00	46.00		-2.10	L 1

Freq.	= Emission frequency in MHz
Raw dBuV	= Uncorrected Analyzer/Receiver reading
Limit dBuV	= Limit stated in standard
Margin dB	= Reading in reference to limit
Note	= Current carrying line of reading
""	= The emission level complied with the Average limits, with at least 2 dB margin, so no further recheck.

LINE CONDUCTED EMISSION LIMIT

Frequency	Maximum RF Line Voltage		
	Q.P.(dBuV)	AVERAGE(dBuV)	
150kHz-500kHz	66-56	56-46	
500kHz-5MHz	56	46	
5MHz-30MHz	60	50	

****Note:** The lower limit shall apply at the transition frequency.

MEASUREMENT PROCEDURE (PRELIMINARY RADIATED EMISSION TEST)

- 1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN 55022.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- 4) The EUT received DC5V from the adapter and PC, then the adapter and PC received AC230V/50Hz power through the outlet socket under the turntable. All support equipments received AC230V/50Hz power from socket under the turntable, if any.
- 5) The antenna was placed at 10 meter away from the EUT as stated in EN 55022. The antenna connected to the Analyzer via a cable and at times a pre-amplifier would be used.
- 6) The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.

Preliminary Radiated Emission Test						
Frequency Range Investig	30 MHz TO	1000 MHz				
Mode of operation	Date	Data Report No.	Worst Mode			
SATA DISK	2006-07-28	Y-103_0(H, V)	\boxtimes			
IDE DISK	2006-07-28	Y-103_1(H, V)				

7) The following test mode(s) were scanned during the preliminary test:

Then, the EUT and cable configuration, antenna position, polarization and turntable position of the above highest emission level were recorded for final testing.

MEASUREMENT PROCEDURE (FINAL RADIATED EMISSION TEST)

- 1) EUT and support equipment were set up on the turntable as per step 7 of the preliminary test.
- 2) The Analyzer / Receiver scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and Q.P./Peak reading is presented.
- 4) The test data of the worst case condition(s) was reported on the Summary Data page.

Freq. (MHz)	Raw Data (dBuV/m)	Corr. Factor (dB)	Emiss. Level (dl	Limits BuV/m)	Margin (dB)	Reading Type P/Q		
====== xx.xxx	14.03	12.25	26.28	30.00	-3.72	Р		
Fi	req.			= Emission	frequency in M	lHz		
R	aw Data (dBu	V/m)		= Uncorrect	= Uncorrected Analyzer / Receiver reading			
С	orr. Factor (dE	B)		= Correction	= Correction factors of antenna factor and cable loss			
E	miss. Level			= Raw readi	ng converted to	o dBuV/m and CF added		
L	imit dBuV/m			= Limit state	ed in standard			
Margin dB			= Reading in reference to limit					
Р	Р			=Peak Reading				
Q	Q				=Quasi-peak			

Data Sample:

RADIATED EMISSION LIMIT

Frequency (MHz)	Distance (m)	Maximum Field Strength Limit (dBuV/m/ Q.P.)
30-230	10	30
230-1000	10	37

****Note:** The lower limit shall apply at the transition frequency.

BLOCK DIAGRAM OF TEST SETUP

System Diagram of Connections between EUT and Simulators

EUT :

USB2.0 IDE/SATA ADAPTER

Trade Name : UNITEK Model Number : Y-103



SUMMARY DATA

(LINE CONDUCTED TEST)

Model Number: Y-103

Location: Site G

Test Mode: SATA DISK

Test Results: Passed

Temperature: 25°C

Humidity: 55%RH

FREQ	PEAK	Q.P.	AVG	Q.P.	AVG	Q.P.	AVG	NOTE
MHz	RAW	RAW	RAW	Limit	Limit	Margin	Margin	
	dBuV	dBuV	dBuV	dBuV	dBuV	dB	dB	
0.209	42.94			64.31	54.31		-11.37	L1
0.272	40.87			62.50	52.50		-11.63	L1
0.342	41.88			60.49	50.49		-8.61	L1
0.483	43.67			56.47	46.47		-2.80	L1
1.180	39.37			56.00	46.00		-6.63	L1
4.364	41.20			56.00	46.00		-4.80	L1
0.246	4 4 4 4			(0.20	50.20		5.05	1.2
0.346	44.44			60.39	50.39		-5.95	L2
0.483	45.63	44.78	44.27	56.47	46.47	-11.69	-2.20	L2
1.184	43.25	42.57	41.99	56.00	46.00	-13.43	-4.01	L2
3.955	45.23	43.42	41.60	56.00	46.00	-12.58	-4.40	L2
4.517	46.12	42.52	38.64	56.00	46.00	-13.48	-7.36	L2
5.078	36.16	25.69	18.62	60.00	50.00	-34.31	-31.38	L2

(The chart below shows the highest readings taken from the final data)

L1 = Line One (Hot side) / L2 = Line Two (Neutral side)

****NOTE:** "----" denotes the emission level was or more than 2dB below the Average limit, so no re-check anymore.

SUMMARY DATA

(RADIATED EMISSION TEST)

Model Number: Y-103

Test Mode: SATA DISK

Test Results: Passed

Temperature: 25°C

Location: Site G

Polar: Vertical / Horizontal

Test Distance: 10m

Humidity: 55%RH

(The chart belo	w shows the hig	ghest readings	taken from the fi	nal data)			
	I	Frequency Rar	nge Investigated	l (30 MHz TO	O 1000 MHz)	
Freq (MHz)	Meter Reading (dBuV/m)	C.F. (dBuV/m)	Corrected Reading (dBuV/m)	Limits (dBuV/ m)	Margin (dB)	Reading Type P/Q	Pol. H/V
44.740	42.08	-23.70	18.38	30.00	-11.62	Q	V
150.021	44.71	-21.39	23.32	30.00	-6.68	Q	V
180.000	43.91	-18.41	25.50	30.00	-4.50	Q	V
210.030	36.42	-18.24	18.18	30.00	-11.82	Q	V
602.784	32.76	-6.26	26.50	37.00	-10.50	Q	V
659.053	31.67	-7.58	24.09	37.00	-12.91	Q	V
119.104	44.61	-19.29	25.32	30.00	-4.68	Р	Н
180.037	39.29	-20.49	18.80	30.00	-11.20	Q	Н
210.222	45.62	-20.25	25.37	30.00	-4.63	Р	Н
225.012	44.61	-16.72	27.89	30.00	-2.11	Р	Н
240.006	47.92	-19.80	28.12	37.00	-8.88	Р	Н
658.980	38.72	-6.09	32.63	37.00	-4.37	Р	Н

C.F.(Correction Factor)=Antenna Factor + Cable Loss - Amplifier Gain (+ Attenuator 6dB)

Corrected Reading = *Metering Reading* + *C.F.*

Margin=Corrected Reading - Limits

P=Peak Reading H=Horizontal Polarization/Antenna

Q=Quasi-peak V=Vertical Polarization/Antenna

Comments: N/A

SECTION 2 EN 61000-3-2 & EN 61000-3-3 (POWER HARMONICS & VOLTAGE FLUCTUATION / FLICKER)

POWER HARMONICS MEASUREMENT

Port	: AC mains
Basic Standard	: EN 61000-3-2 :2000
Limits	: V CLASS A ; CLASS D
Temperature	: 25°C
Humidity	: 55%

VOLTAGE FLUCTUATION/FLICKER MEASUREMENT

Port	: AC mains
Basic Standard	: EN 61000-3-3 : 1995+A1:2001
Limits	: §5 of EN 61000-3-3
Temperature	: 25°C
Humidity	: 55%

Block Diagram of Test Setup:



Result:

Please see the attached test data

Harmonics – Class-A per A-14(Run time)

EUT: USB2.0 IDE/SATA ADAPTERTested by: VeasonTest category: Class-A per A-14 (European limits)Test Margin: 100Test date: 06-7-27Start time: 15:43:25End time: 15:46:07Test duration (min): 2.5Data file name: H-002430.cts_dataComment: Y-103Customer: TECH-TOP TECHNOLOGY LIMITED

Test Result: Pass

Source qualification: Normal

Current & voltage waveforms



Harmonics and Class A limit line

European Limits



Current Test Result Summary (Run time)

EUT: U	SB2.0 IDE/SATA	ADAPTER			Tested by: V	eason	
Test cat	egory: Class-A p	er A-14 (Eur	opean limits)	1	Test Margin:	: 100	
Test dat	te: 06-7-27	Sta	rt time: 15:4	3:25	End time: 15	:46:07	
Test du	ration (min): 2.5	Da	ta file name:	H-002430.cts_dat	a		
Comme	ent: Y-103						
Custom	er: TECH-TOP	TECHNOLC	OGY LIMITH	ED			
Test Re	sult: Pass		Source	qualification: N	ormal		
Highest	parameter valu	es during test					
0	V_RMS (Volts)	: 230.22					
	I_Peak (Amps):	: 0.350		I_RMS (Amps):	0.065		
	I_Fund (Amps)	: 0.032		Crest Factor:	5.435		
	Power (Watts):	5		Power Factor:	0.345		
Harm#	Harms(avg)	100%Limit	%of Limit	Harms(max)	150%Limit	%of Limit	Status
2	0.001	1.080	0.1	0.002	1.620	0.13	Pass
3	0.020	2.300	0.9	0.021	3.450	0.62	Pass
4	0.001	0.430	0.3	0.002	0.645	0.37	Pass
5	0.019	1.140	1.7	0.020	1.710	1.16	Pass
6	0.001	0.300	0.3	0.002	0.450	0.41	Pass
7	0.019	0.770	2.4	0.019	1.155	1.66	Pass
8	0.001	0.230	0.5	0.002	0.345	0.53	Pass
9 10	0.018	0.400	4.5	0.018	0.000	3.04	Pass
10	0.001	0.104	0.0 5 2	0.002	0.270	0.00	r ass Pass
11	0.017	0.350	5. <u>2</u> 0.6	0.017	0.493	0.72	1 ass Pass
13	0.011	0.133	7.6	0.002	0.250	5.14	Pass
14	0.001	0.131	0.7	0.002	0.197	0.80	Pass
15	0.015	0.150	9.9	0.015	0.225	6.66	Pass
16	0.001	0.115	0.8	0.001	0.173	0.86	Pass
17	0.014	0.132	10.2	0.014	0.199	6.87	Pass
18	0.001	0.102	0.8	0.001	0.153	0.88	Pass
19	0.012	0.118	10.3	0.012	0.178	6.90	Pass
20	0.001	0.092	0.8	0.001	0.138	0.90	Pass
21	0.011	0.107	10.0	0.011	0.161	6.77	Pass
22	0.001	0.084	0.8	0.001	0.125	0.90	Pass
23	0.009	0.098	9.6	0.009	0.147	6.46	Pass
24	0.001	0.077	0.8	0.001	0.115	0.87	Pass
25 26	0.008	0.090	8.9	0.008	0.135	5.99	Pass
20	0.000	0.071	0.8	0.001	0.100	0.04 5 <i>4</i> 1	Pass
27	0.007	0.065	0.0	0.007	0.123	0.76	1 ass Pass
20	0.000	0.000	69	0.001	0.077	472	I ass Pass
30	0.000	0.061	0.7	0.005	0.092	0.74	Pass
31	0.004	0.073	5.8	0.004	0.109	3.94	Pass
32	0.000	0.058	0.6	0.001	0.086	0.65	Pass
33	0.003	0.068	4.6	0.003	0.102	3.15	Pass
34	0.000	0.054	0.5	0.000	0.081	0.61	Pass
35	0.002	0.064	3.5	0.002	0.096	2.37	Pass
36	0.000	0.051	0.4	0.000	0.077	0.53	Pass
37	0.001	0.061	2.3	0.001	0.091	1.61	Pass
38	0.000	0.048	0.4	0.000	0.073	0.50	Pass
39	0.001	0.058	1.5	0.001	0.087	1.03	Pass
40	0.000	0.046	0.4	0.000	0.069	0.46	Pass

Voltage Source Verification Data (Run time)

EUT: U Test cat	SB2.0 IDE/SATA A egory: Class-A per	ADAPTE	R Iropean limits)	T T	ested by: Veason est Margin: 100
Test dat	e: 06-7-27	S	tart time: 15:43:25	Ē	and time: 15:46:07
Test du	ration (min): 2.5	Ď	ata file name: H-002	2430.cts data	
Comme	nt: Y-103			—	
Custom	er: TECH-TOP TI	ECHNOL	OGY LIMITED		
Test Re	sult: Pass		Source quali	fication: Norn	nal
Highest	parameter values	during te	st:		
	Voltage (Vrms):	230.22			
	I_Peak (Amps):	0.350	I_RI	MS (Amps):	0.065
	I_Fund (Amps):	0.032	Cres	st Factor:	5.435
	Power (Watts):	5	Pow	er Factor:	0.345
Harm#	Harmonic	s V-rms	Limit V-rms	% of Limi	t Status
2		0.184	0.460	39.93	3 ОК
3		0.481	2.072	23.2	1 OK
4		0.093	0.460	20.20	6 OK
5		0.043	0.921	4.6	6 OK
6		0.046	0.460	9.9	0 OK
7		0.030	0.690	4.4	0 OK
8		0.031	0.460	6.6.	3 OK
9		0.012	0.460	2.5	5 OK
10		0.029	0.460	6.2	7 OK
11		0.021	0.230	9.3	0 OK
12		0.019	0.230	8.4	1 OK
13		0.017	0.230	7.4	7 OK
14		0.010	0.230	4.42	2 OK
15		0.015	0.230	6.6.	3 OK
16		0.016	0.230	7.1	O OK
17		0.021	0.230	9.2	7 OK
18		0.017	0.230	7.5	8 OK
19		0.016	0.230	6.74	4 OK
20		0.012	0.230	5.28	8 OK
21		0.016	0.230	6.9	6 OK
22		0.010	0.230	4.3	6 OK
23		0.015	0.230	6.6	O OK
24		0.008	0.230	3.5	6 OK
25		0.012	0.230	5.3.	3 OK
26		0.012	0.230	5.3	U OK
27		0.012	0.230	5.30	S OK
28		0.011	0.230	4.64	4 OK
29			0.230	3.14	4 OK
30 21		0.010	0.230	4.4	
31		0.009	0.230	3.8	
54 22		0.007	0.230	3.00 2.54	
33 24		0.008	0.230	3.50 2.50	
34 25		0.000	0.230	2.5.	
35 26		0.007	0.230	2.9.	
30 27		0.004	0.230	1./0	
3/		0.002	0.230	0.9	
30 20		0.004	0.230	1.0	
39 40		0.000	0.230 A 73A	2.43	
40		0.005	0.430	2.0.	

Flicker Test Summary (Run time)

EUT: USB2.0 IDE/SATA AD	APTER	Tested by: Veason
Test category: All parameter	rs (European limits)	Test Margin: 100
Test date: 06-7-27	Start time: 15:48:35	End time: 15:58:48
Test duration (min): 10	Data file name: F-002431.c	cts_data
Comment: Y-103		
Customer: TECH-TOP TEC	CHNOLOGY LIMITED	

Test Result: Pass

Status: Test Completed

Pst_i and limit line

European Limits



Time is too short for Plt plot

Parameter values recorded during the test:

Vrms at the end of test (Volt):	230.16			
Highest dt (%):	0.00	Test limit (%):	3.30	Pass
Highest dc (%):	0.00	Test limit (%):	3.30	Pass
Highest dmax (%):	0.00	Test limit (%):	4.00	Pass
Highest Pst (10 min. period):	0.001	Test limit:	1.000	Pass
Highest Plt (2 hr. period):	0.001	Test limit:	0.650	Pass

SECTION 3 IEC 61000-4-2 (ELECTROSTATIC DISCHARGE)

ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port :	Enclosure
Basic Standard :	IEC 61000-4-2: 2001
Test Level :	± 8 kV (Air Discharge)
	\pm 4 kV (Contact Discharge)
Performance Criteria :	B (Standard require)
Temperature/Humidity :	25°C/55%

Block Diagram of Test Setup:

(The 470 k ohm resistors are installed per standard requirement)



Ground Reference Plane

Test Procedure:

- 1. The EUT was located 0.1 m minimum from all side of the HCP.
- 2. The support units were located 1 m minimum away from the EUT.
- 3. Set up the EUT with the related support equipments; Run the Copy.bat program of transferring data from PC to hard disk in windows XP; Make sure EUT work normally during the test.
- 4. Active the communication function if the EUT with such port(s).
- 5. As per the requirement of EN 55024; applying direct contact discharge at the sides other than front of EUT at minimum 50 discharges (25 positive and 25 negative) if applicable, can't be applied direct contact discharge side of EUT then the indirect discharge shall be applied. One of the test points shall be subjected to at least 50 indirect discharge (contact) to the front edge of horizontal coupling plane.
- 6. Other parts of EUT where it is not possible to perform contact discharge then selecting appropriate points of EUT for air discharge, a minimum of 10 single air discharges shall be applied.
- 7. The application of ESD to the contact of open connectors is not required.
- 8. Putting a mark on EUT to show tested points. The following test condition was followed during the tests.
- **Note:** As per the A2 to IEC 61000-4-2, a bleed resistor cable is connected between the EUT and HCP during the test.

The electrostatic discharges were applied as follows:

Amount of	Voltage	Coupling	Result (Pass/Fail)
Discharges			
Mini 25 /Point	$\pm 2kV; \pm 4kV$	Contact Discharge	No discharge point
Mini 25 /Point	$\pm 2kV; \pm 4kV$	Indirect Discharge HCP (Front)	Pass
Mini 25 /Point	$\pm 2kV; \pm 4kV$	Indirect Discharge VCP (Left)	Pass
Mini 25 /Point	$\pm 2kV; \pm 4kV$	Indirect Discharge VCP (Back)	Pass
Mini 25 /Point	$\pm 2kV; \pm 4kV$	Indirect Discharge VCP (Right)	Pass
Mini 10 /Point	$\pm 2kV; \pm 4kV; \pm 8kV$	Air Discharge	No discharge point



Performance & Result:

- **Criterion A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- Criterion B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- **Criterion C:** Temporary loss of function is allowed, provided the functions self-recoverable or can be restored by the operation of controls.

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SECTION 4 IEC 61000-4-3 (RADIATED ELECTROMAGNETIC FIELD) RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Port	: Enclosure
Basic Standard	: IEC 61000-4-3:2002
Requirements	: 3 V/m with 80% AM. 1kHz Modulation.
Performance Criteria	: A (Standard require)
Temperature	: 25°C
Humidity	: 55%

Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT was located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity. The support units were located outside of the uniformity area, but the cable(s) connected with EUT were exposed to the calibrated field as per IEC 61000-4-3.
- 2. Set up the EUT with the related support equipments; Run the Copy.bat program of transferring data from PC to hard disk in windows XP; Make sure EUT work normally during the test.
- 3. Setting the testing parameters of RS test software per IEC 61000-4-3.
- 4. Performing the pre-test at each side of with double specified level (3V/m) at 1% steps.
- 5. From the result of pre-test in step 5, choose the worst side of EUT for final test from 80 MHz to 1000 MHz at 1% steps.
- 6. Recording the test result in following table.
- 7. It is not necessary to perform test as per annex A of EN 55024 if the EUT doesn't belong to TTE product.

IEC 61000-4-3 test conditions:

Test level	: 3V/m						
Steps	:1% of fundation	mental					
Dwell Time	: 1 sec						
Range (MHz)	Field	Modulation	Polarity	Position (°)	Result (Pass/Fail)		
80-1000	3V/m	Yes	Н	Front	Pass		
80-1000	3V/m	3V/m Yes V Front Pass					
80-1000	3V/m	Yes	Н	Right	Pass		
80-1000	3V/m	Yes	V	Right	Pass		
80-1000	3V/m	Yes	Н	Back	Pass		
80-1000	3V/m	Yes	V	Back	Pass		
80-1000	3V/m	Yes	Н	Left	Pass		
80-1000	3V/m	Yes	V	Left	Pass		



Performance & Result:

- V Criterion A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
 - **Criterion B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
 - **Criterion C:** Temporary loss of function is allowed, provided the functions self-recoverable or can be restored by the operation of controls.

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SECTION 5 IEC 61000-4-4 (FAST TRANSIENTS/BURST)

FAST TRANSIENTS/BURST IMMUNITY TEST

Port	: On Power Supply Lines
Basic Standard	: IEC 61000-4-4: 2001
Requirements	:+/-1KV for Power Supply Lines
Performance Criteria	: B (Standard require)
Temperature	: 25°C
Humidity	: 55%

Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground reference plane.
- 2. A 1.0 meter long power cord was attached to EUT during the test.
- 3. The length of communication cable between communication port and clamp was keeping within 1 meter.
- 4. Set up the EUT with the related support equipments; Run the Copy.bat program of transferring data from PC to hard disk in windows XP; Make sure EUT work normally during the test.
- 5 .Related peripherals work during the test.
- 6. Recording the test result as shown in following table.

Test conditions:

Impulse Frequency: 5kHz Tr/Th: 5/50ns Burst Duration: 15ms Burst Period: 300ms

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)
L	+/- 1	Direct	Pass
Ν	+/- 1	Direct	Pass
L+N	+/- 1	Direct	Pass

Performance & Result:

- **V** Criterion A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
 - **Criterion B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
 - **Criterion C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.



SECTION 6 IEC 61000-4-5 (SURGE IMMUNITY)

SURGE IMMUNITY TEST

Port	: On Power Supply Lines
Basic Standard	: IEC 61000-4-5: 2001
Requirements	: +/- 1kV (Line to Line)
	: +/- $2kV$ (Line to Ground)
Performance Criteria	:B (Standard require)
Temperature	: 25°C
Humidity	: 55%

Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground floor.
- 2. Set up the EUT with the related support equipments; Run the Copy.bat program of transferring data from PC to hard disk in windows XP; Make sure EUT work normally during the test.
- 3. Recording the test result as shown in following table.

Test conditions:

Voltage Waveform	: 1.2/50 <i>u</i> s
Current Waveform	: 8/20 <i>u</i> s
Polarity	: Positive/Negative
Phase angle	$:0^{\circ}, 90^{\circ}, 270^{\circ}$
Number of Test	: 5

Coupling Line	Voltage (kV)	Polarity	Coupling Method	Result (Pass/Fail)
L1-L2	1	Positive	Capacitive	Pass
L1-L2	1	Negative	Capacitive	Pass

Performance & Result:

V Criterion A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.

Criterion B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.

Criterion C: Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.



SECTION 7 IEC 61000-4-6(CONDUCTED DISTURBANCE/INDUCED BY RADIO-FREQUENCY FIELD)

Port	: On Power Supply Lines
Basic Standard	: IEC 61000-4-6: 2001
Requirements	: 3V with 80% AM. 1kHz Modulation
Injection Method	: CDN
Performance Criteria	: A (Standard require)
Temperature	: 25°C
Humidity	: 55%

Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
- 2. Set up the EUT with the related support equipments; Run the Copy.bat program of transferring data from PC to hard disk in windows XP; Make sure EUT work normally during the test.
- 3. Related peripherals work during the test.
- 4. Setting the testing parameters of CS test software per IEC 61000-4-6.
- 5. Recording the test result in following table.

Test conditions:

Frequency Range: 0.15MHz-80MHzFrequency Step: 1% of fundamental

Dwell Time : 1 sec

Range (MHz)	Field	Modulation	Result (Pass/Fail)
0.15-80	3V	Yes	Pass

Performance & Result:

- V Criterion A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
 - Criterion B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
 - Criterion C: Temporary loss of function is allowed, provided the functions self-recoverable or can be restored by the operation of controls.



SECTION 8 IEC 61000-4-11 (VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS)

VOLTAGE DIPS / SHORT INTERRUPTIONS

Port	: On Power Supply Lines
Basic Standard	: IEC 61000-4-11: 2001
Requirement	: PHASE ANGLE 0, 45, 90, 135, 180, 225, 270, 315 degrees

Voltage	Test Level % U _T	Reduction (%)	Duration (periods)	Performance Criteria
Dips	<5	>95	0.5	В
	70	30	25	С
Voltago	Test Level	Reduction	Duration	Performance
Voltage	% U _T	(%)	(periods)	Criteria
interceptions	<5	>95	250	С

Test Interval: Min. 10 sec.Temperature: 25°CHumidity: 55%

Block Diagram of Test Setup:



Test Procedure:

- 1. The EUT and support units were located on a wooden table, 0.8 m away from ground floor.
- 2. Set up the EUT with the related support equipments; Run the Copy.bat program of transferring data from PC to hard disk in windows XP; Make sure EUT work normally during the test.
- 3. Setting the parameter of tests and then Perform the test software of test simulator.
- 4. Conditions changes to occur at 0 degree crossover point of the voltage waveform.
- 5. Recording the test result in test record form.

Test conditions:

The duration with a sequence of three dips/interruptions with interval of 10 s minimum (Between each test event)

Voltage Dips:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Meet Performance Criteria
0	100	0.5	EUT shut down, but can recover by itself	В
70	30	25	EUT shut down, but can recover by itself	В

Voltage Interruptions:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Meet Performance Criteria
0	100	250	EUT shut down, but can recover by itself	В

Performance & Result:

- **Criterion A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- **Criterion B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- **Criterion C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

